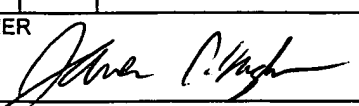


Sheet 1 of 1

Form PTO-449	U.S. Dept. of Commerce Patent and Trademark Office	Attorney Docket No.:	Serial No.: 09/960,479					
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		Applicant: Tokuda, Mitsuo, et al.						
		Filing Date: September 24, 2001	Group:					
U.S. PATENT DOCUMENTS								
Initial*	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE	
JH	AA	4 4 7 6 3 8 6	10/09/84	Reid, et al.	250	310		
JH	AB	5 2 7 0 5 5 2	12/14/93	Ohnishi, et al.	250	307		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO	
JH	AC	0 9 2 7 8 8 0	07/21/98	EU Application	G01N	1/28	X	
	AD							
	AE							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
JH	AF	Ohnishi, T., et al., "A new focused-ion-beam microsampling technique for TEM observation of site-specific areas." ISTFA '99. Proceedings of the 25 th International Symposium for Testing and Failure Analysis. ASM Int. 1999, pp. 449-53 (14-18 Nov. 1999). Materials Parks, OH, USA						
JK	AG	Pawley, James B., "A Dual Needle Piezoelectric Micromanipulator for the Scanning Electron Microscope." The Review of Scientific Instruments, Vol. 43, No. 4, April 1972.						
	AH							
EXAMINER 				DATE CONSIDERED 8/1/03				
*EXAMINER: Initial if references considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								